

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/672,073	WEDEL ET AL.	
Examiner	Art Unit	
Michael J. Hicks	2165	

SEARCHED					
Class	Subclass	Date	Examiner		
707	101	7/27/2006	Myt		
707	102	7/27/2006			
707	10	7/27/2006	\ \		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
707	101	7/27/2006	NAH		
707	102	7/27/2006			
707	10	7/27/2006			
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SEARCH NOT)
	DATE	EXMR
Inventor Name Search	7/27/2006	MIT
Assignee Search	7/27/2006	
Review of Previously Identified Prior Art	7/27/2006	
Updated Patent Database Search - East	7/27/2006	
Updated NPL Search - ACM - Google - Google Scholar	7/27/2006	
Consulted with Examiner Apu Mofiz	7/27/2006	